Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/820,421	CHIU ET AL.
	Examiner	Art Unit
	John Juba, Jr.	2872

SEARCHED

Class	Subclass	Date	Examiner
359	486	3/21/2005	JJ
UPDATED	ABOVE	8/25/2005	JJ
359	572	8/25/2005	JJ
359	576	8/25/2005	JJ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
INSPEC™ search: (nanoimprint or (nano adj imprint)) and (polariz$3 or polaris$3)	3/21/2005	JJ
INSPEC™ search: ((wire adj grid) or (polarizer$1 or polariser$1) and (double adj layer)	3/21/2005	JJ
EAST text search notes attached	3/21/2005	JJ
UPDATED previous EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached history	8/24/2005	JJ
Further EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) see attached history	8/25/2005	JJ